



# Power MOSFETS

## DATASHEET

**LM1A060NAP3A**

N-Channel  
Enhancement Mode MOSFET

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Quality Management Systems  
ISO 9001:2015 Certificate

## N-Channel Enhancement Mode MOSFET

Pin Description		Ordering Information		
 TO-220-3L (TOP view)	 Symbol	Symbol	N-Channel	Unit
		$V_{DSS}$	100	V
		$R_{DS(ON)-Max}$	6.4	$m\Omega$
		$I_D$	102	A

### Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS Tested

### Applications

- Portable Equipment
- Battery Powered System

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1A060NAP3A	TO-220-3L	Tube	50 / Tube	1A060 □□□□□□

Note : □□□□□□ = Lot Code

### Absolute Maximum Ratings ( $T_J=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
$V_{DSS}$	Drain-Source Voltage	100	V
$V_{GSS}$		$\pm 20$	
$T_J$	Maximum Junction Temperature	150	$^\circ C$
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ C$
$I_{DM}^{(1)}$	Pulse Drain Current Tested	$T_c=25^\circ C$	A
$I_D$	Continuous Drain Current	$T_c=25^\circ C$	A
		$T_c=100^\circ C$	
$P_D$	Maximum Power Dissipation	$T_c=25^\circ C$	W
		$T_c=100^\circ C$	
$I_{AS}^{(2)}$	Avalanche Current, Single pulse	L=0.1mH	A
$E_{AS}^{(2)}$	Avalanche Energy, Single pulse	L=0.1mH	mJ

### Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	1 $^\circ C/W$
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	Steady State	62.5 $^\circ C/W$

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature  $150^\circ C$

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz.

N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_{DS}=250\mu\text{A}$	100	-	-	V
$\mathbf{I_{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=80\text{V}$ , $V_{GS}=0\text{V}$	-	-	1	$\mu\text{A}$
$\mathbf{V_{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=250\mu\text{A}$	1	2	3	V
$\mathbf{I_{GSS}}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	-	-	$\pm 100$	$\text{nA}$
$\mathbf{R_{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}$ , $I_{DS}=20\text{A}$	-	5.3	6.4	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_{DS}=20\text{A}$	-	7	9	
$\mathbf{g_{fs}}$	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_{DS}=10\text{A}$	-	3.2	-	S
<b>Dynamic Characteristics <sup>⑤</sup></b>						
$\mathbf{R_G}$	Gate Resistance	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , Freq.=1MHz	-	1.8	-	$\Omega$
$\mathbf{C_{iss}}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=50\text{V}$ , Freq.=1MHz	-	3010	-	$\text{pF}$
$\mathbf{C_{oss}}$	Output Capacitance		-	540	-	
$\mathbf{C_{rss}}$	Reverse Transfer Capacitance		-	21	-	
$\mathbf{t_{d(ON)}}$	Turn-on Delay Time	$V_{GS}=10\text{V}$ , $V_{DS}=50\text{V}$ , $I_D=1\text{A}$ , $R_{GEN}=3\Omega$	-	11.5	-	$\text{nS}$
$\mathbf{t_r}$	Turn-on Rise Time		-	21	-	
$\mathbf{t_{d(OFF)}}$	Turn-off Delay Time		-	43	-	
$\mathbf{t_f}$	Turn-off Fall Time		-	26	-	
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=4.5\text{V}$ , $V_{DS}=50\text{V}$ $I_D=20\text{A}$	-	32.5	-	$\text{nC}$
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=10\text{V}$ , $V_{DS}=50\text{V}$ , $I_D=20\text{A}$	-	60	-	
$\mathbf{Q_{gs}}$	Gate-Source Charge		-	8.2	-	
$\mathbf{Q_{gd}}$	Gate-Drain Charge		-	16.5	-	
<b>Source-Drain Characteristics</b>						
$\mathbf{V_{SD}}^{\circledast}$	Diode Forward Voltage	$I_{SD}=20\text{A}$ , $V_{GS}=0\text{V}$	-	0.85	1.1	V
$\mathbf{t_{rr}}$	Reverse Recovery Time	$I_F=20\text{A}$ , $V_R=50\text{V}$ $dI_F/dt=100\text{A}/\mu\text{s}$	-	55.7	-	$\text{nS}$
$\mathbf{Q_{rr}}$	Reverse Recovery Charge		-	109	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$ , duty cycle $\leq 2\%$ ).

Note ⑤ : Guaranteed by design, not subject to production testing.

## N-Channel Typical Characteristics

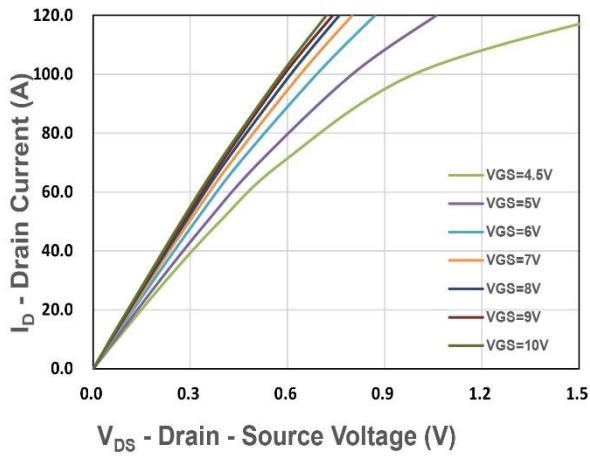


Figure 1. Output Characteristics

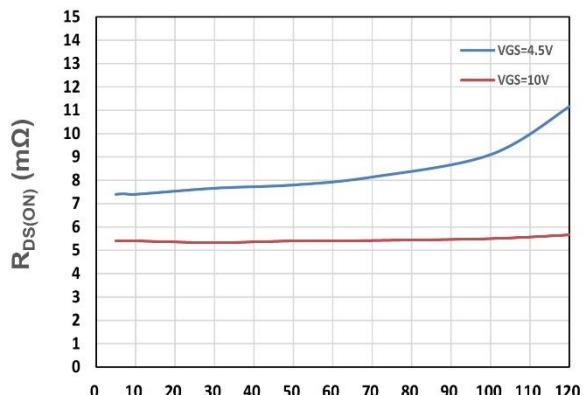


Figure 2. On-Resistance vs. ID

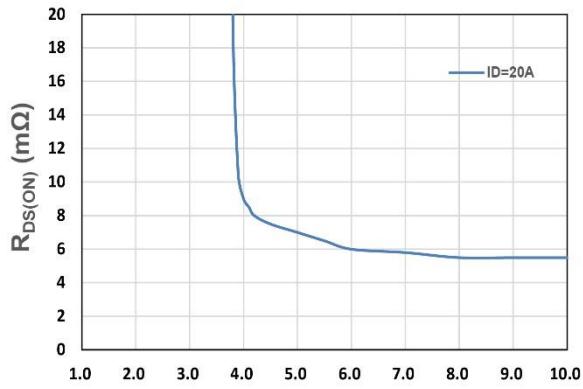


Figure 3. On-Resistance vs. VGS

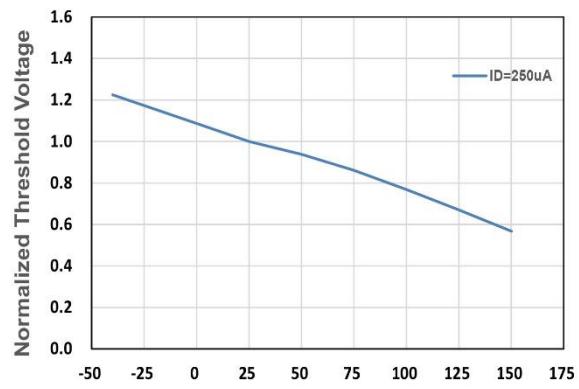


Figure 4. Gate Threshold Voltage

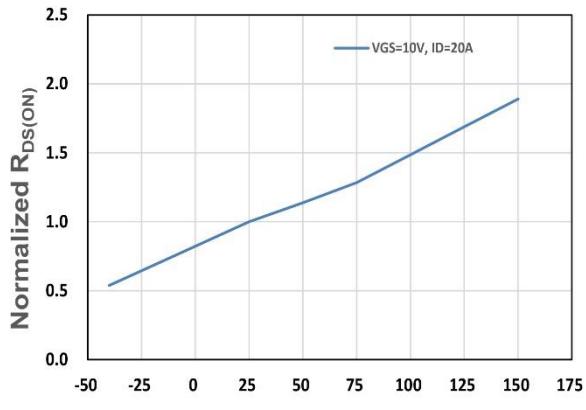


Figure 5. Drain-Source On Resistance

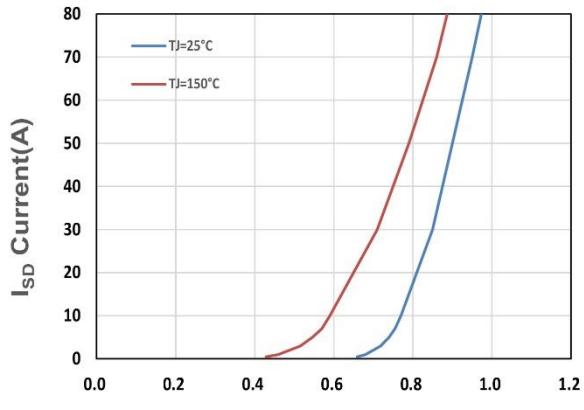
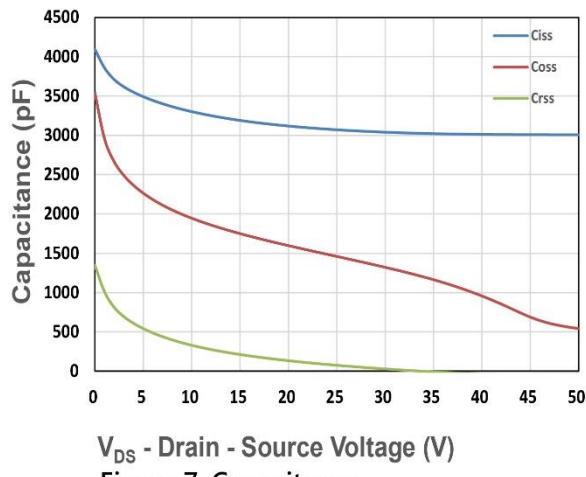


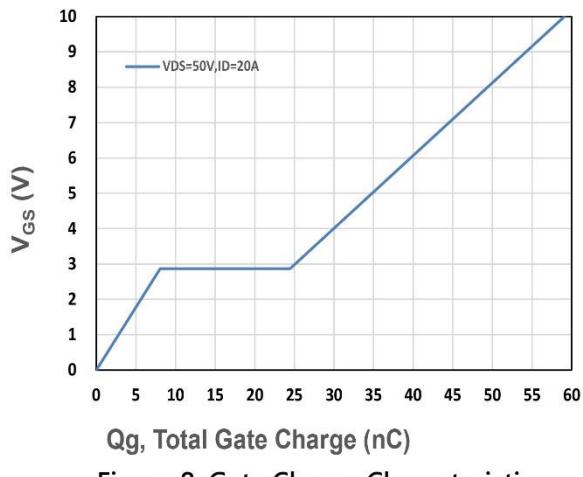
Figure 6. Source-Drain Diode Forward

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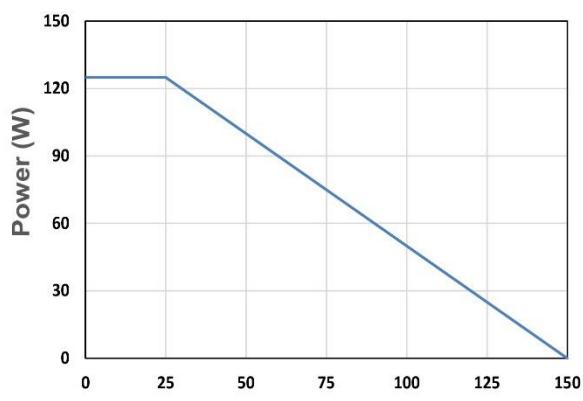
$V_{DS}$  - Drain - Source Voltage (V)

Figure 7. Capacitance



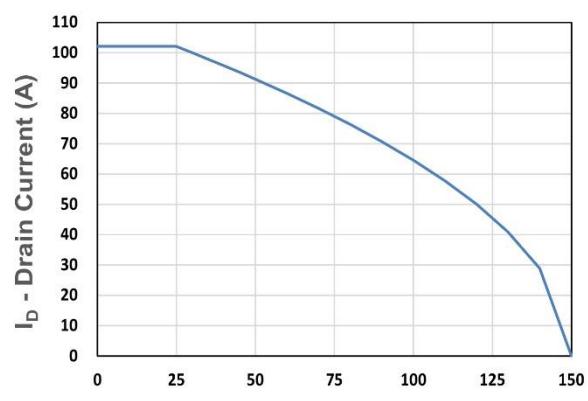
$V_{GS}$  (V)

Figure 8. Gate Charge Characteristics



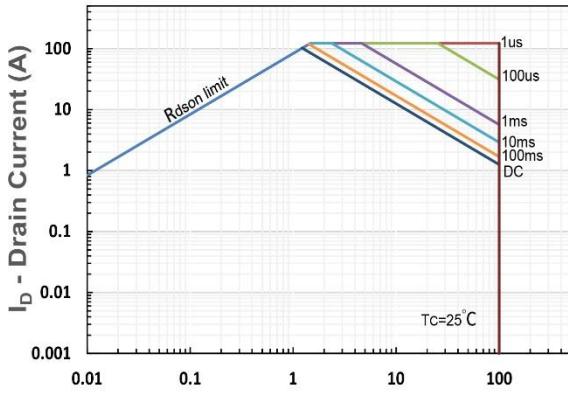
$T_C$  - Case Temperature(°C)

Figure 9. Power Dissipation



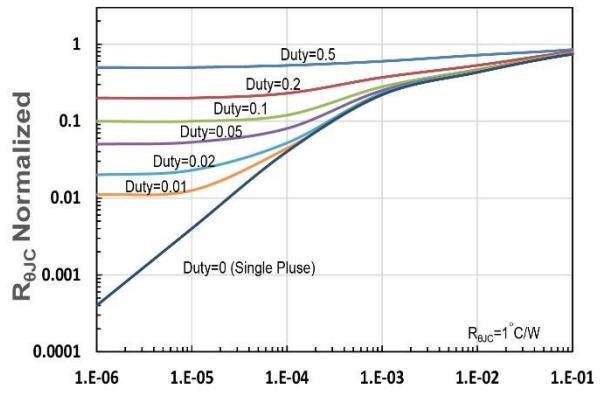
$T_C$  - Case Temperature(°C)

Figure 10. Drain Current



$V_{DS}$  - Drain-Source Voltage (V)

Figure 11. Safe Operating Area



$t_1$ ,Square Wave Pulse Duration(s)

Figure 12.  $R_{θJC}$  Transient Thermal Impedance